

Notice of References Cited	Application/Control No. 10/707,224		Applicant(s)/Patent Under Reexamination SU ET AL.	
	Examiner Matthew G. Kayrish		Art Unit 2653	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,538,970	03-2003	Fujiwara et al.	720/604
*	B	US-4,979,161	12-1990	Verhagen, Johannes P. C. M.	720/619
*	C	US-5,025,339	06-1991	Kanno et al.	360/99.06
*	D	US-5,299,185	03-1994	Sakurai et al.	720/628
*	E	US-5,355,357	10-1994	Yamamori et al.	720/646
*	F	US-5,867,338	02-1999	Ohira et al.	720/627
*	G	US-5,883,871	03-1999	Shihou, Makoto	720/643
*	H	US-6,069,858	05-2000	Endo et al.	720/627
*	I	US-6,091,573	07-2000	Pisano et al.	720/630
*	J	US-6,301,214	10-2001	Yamashita et al.	720/628
*	K	US-6,327,114	12-2001	Otsuki et al.	360/99.06
*	L	US-6,907,612	06-2005	Takeshima et al.	720/605
*	M	US-2003/0107975	06-2003	Satoh, Katsuhisa	369/77.1

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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